

## 100V N-Channel Enhancement Mode MOSFET

### Description

The AP150N10NF uses advanced **APM-SGT<sub>11</sub>** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 100V$   $I_D = 150A$

$R_{DS(ON)} < 4.5m\Omega$  @  $V_{GS}=10V$  (Type: **4.0mΩ**)

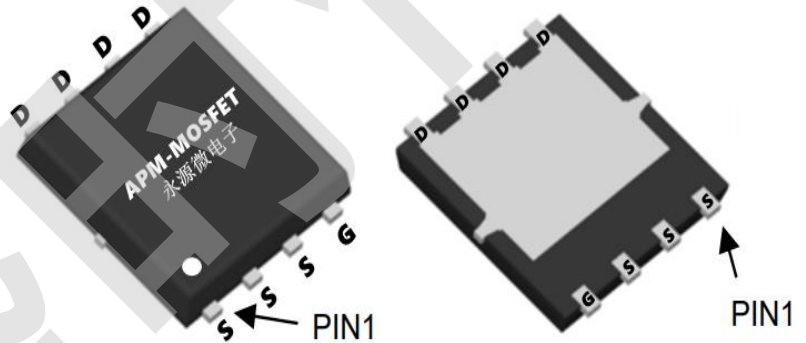
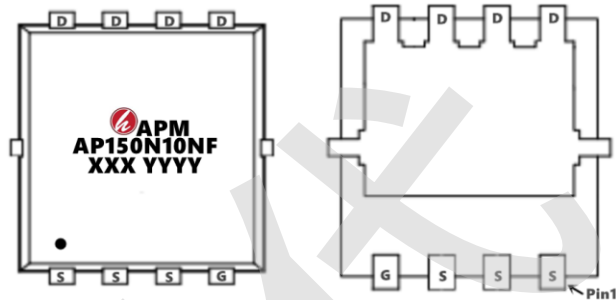
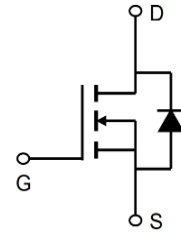
### Application

Isolated DC

Motor control

Synchronous-rectification

**Clip** packaging process



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP120N10NF	PDFN5*6-8L	AP120N10NF XXX YYYY	5000

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_A=25^\circ\text{C}$	Continuous Drain Current <sup>1</sup>	150	A
$I_D@T_A=70^\circ\text{C}$	Continuous Drain Current <sup>1</sup>	96	A
IDM	Pulsed Drain Current <sup>2</sup>	480	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	320	mJ
IAS	Avalanche Current	40	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	131.6	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	25	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	0.95	$^\circ\text{C/W}$

AP150N10NF RVE1.0

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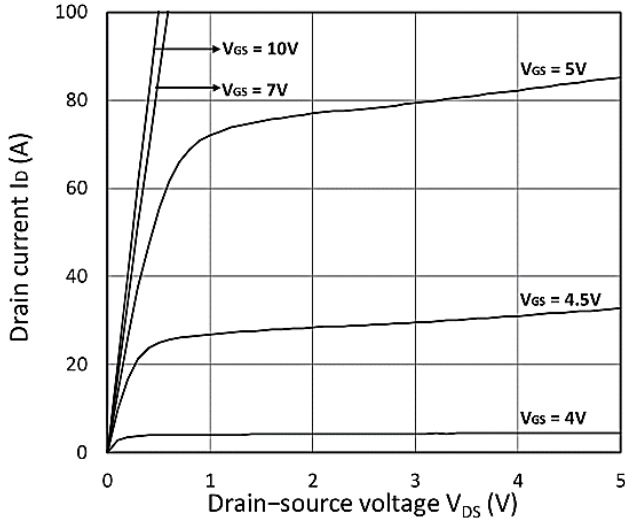
### Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	100	107	-	V
IGSS	Gate-body Leakage current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
IDSS	Zero Gate Voltage Drain Current T <sub>J</sub> =25°C	V <sub>DS</sub> =100V, V <sub>GS</sub> = 0V	-	-	1	μA
	Zero Gate Voltage Drain Current T <sub>J</sub> =100°C		-	-	100	
VGS(th)	Gate-Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.0	3.0	4.0	V
RDS(on)	Drain-Source on-Resistance <sup>4</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	4.1	4.5	mΩ
gfs	Forward Transconductance <sup>4</sup>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 20A	-	62	-	S
Ciss	Input Capacitance	V <sub>DS</sub> = 50V, V <sub>GS</sub> =0V, f =1MHz	-	6865	-	pF
Coss	Output Capacitance		-	740	-	
Crss	Reverse Transfer Capacitance		-	21	-	
R <sub>g</sub>	Gate Resistance	f =1MHz	-	1.3	-	Ω
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 50V, I <sub>D</sub> =20A	-	111.2	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	30.5	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	27.3	-	
td(on)	Turn-on Delay Time	V <sub>GS</sub> =10V, V <sub>DD</sub> =50V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = 20A	-	33	-	ns
t <sub>r</sub>	Rise Time		-	39	-	
td(off)	Turn-off Delay Time		-	67.1	-	
t <sub>f</sub>	Fall Time		-	32	-	
trr	Body Diode Reverse Recovery Time	I <sub>F</sub> = 20A, dI/dt=100A/μs	-	58.7	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	97.3	-	nC
VSD	Diode Forward Voltage <sup>4</sup>	I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	-	1.2	V
I <sub>S</sub>	Continuous Source Current T <sub>C</sub> =25°C	-	-	-	120	A

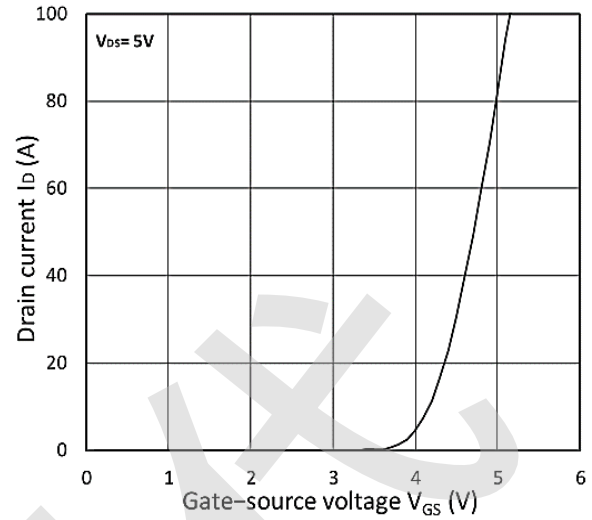
#### Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD=72V,VGS=10V, L=0.1mH IAS=40A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation

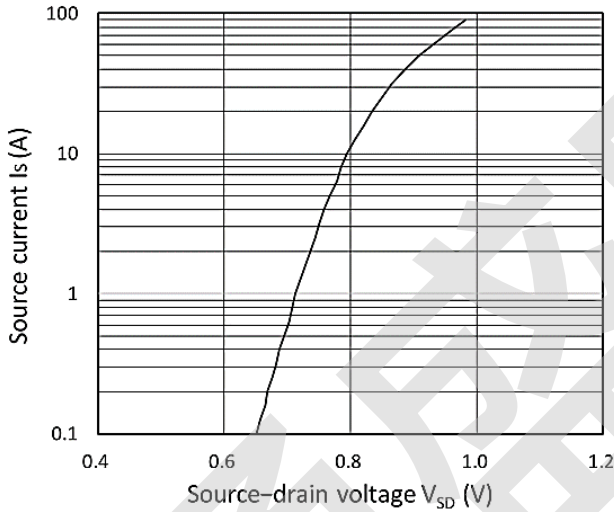
### Typical Characteristics



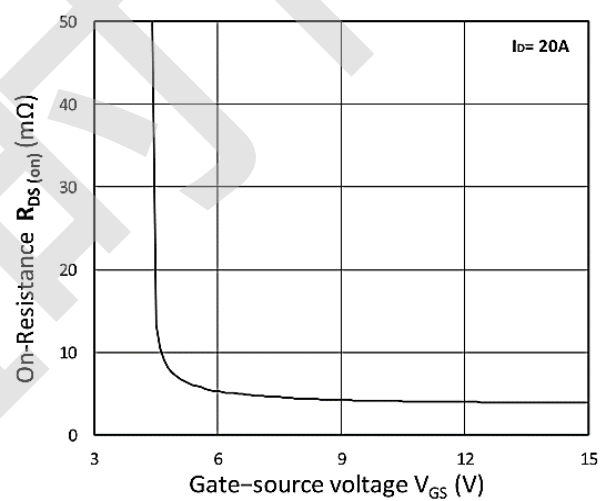
**Figure 1. Output Characteristics**



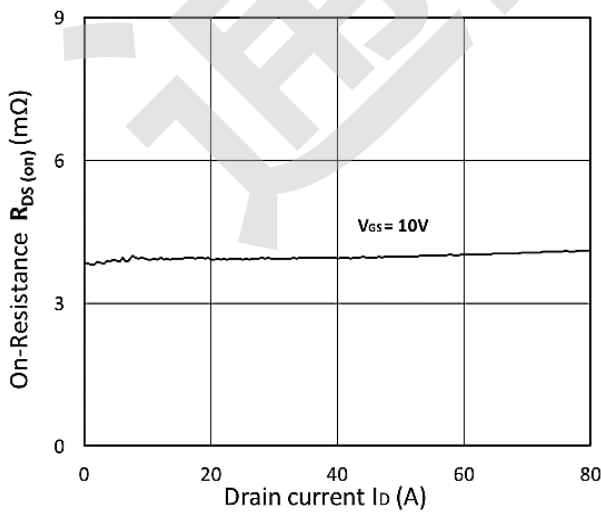
**Figure 2. Transfer Characteristics**



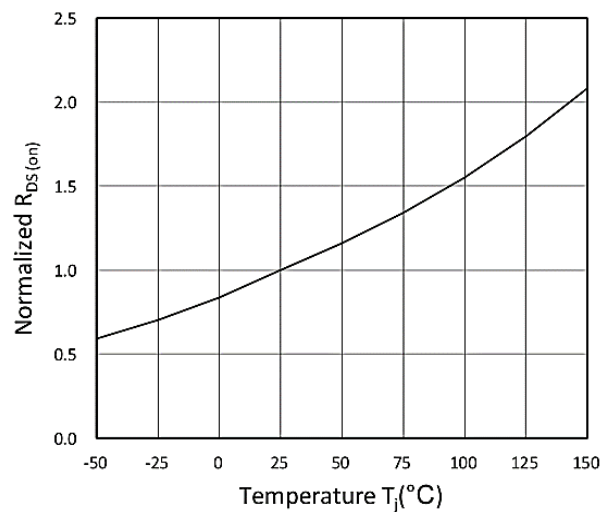
**Figure 3. Forward Characteristics of Reverse**



**Figure 4. RDS(ON) vs. VGS**

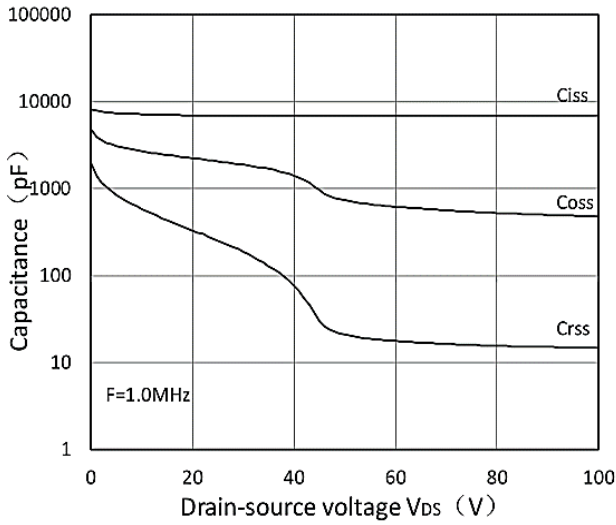


**Figure 5. RDS(ON) vs. ID**

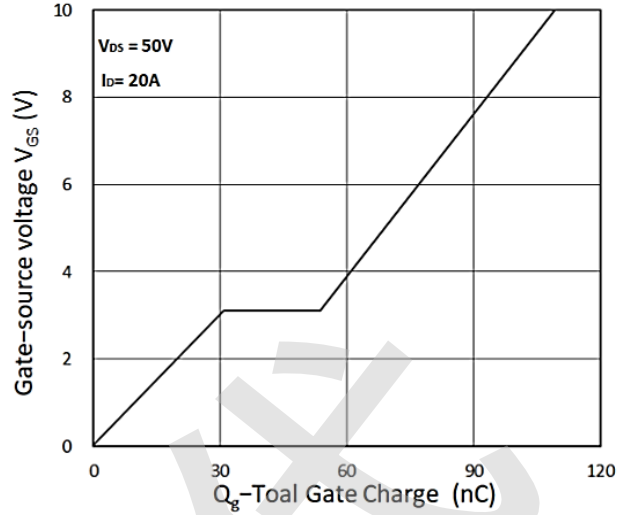


**Figure 6. Normalized RDS(on) vs. Temperature**

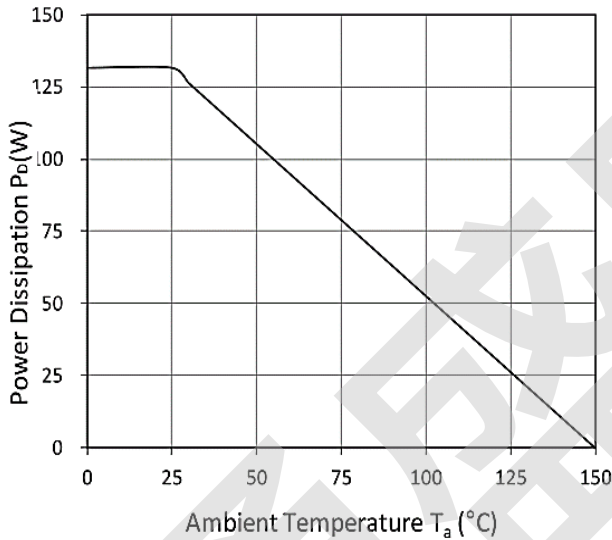
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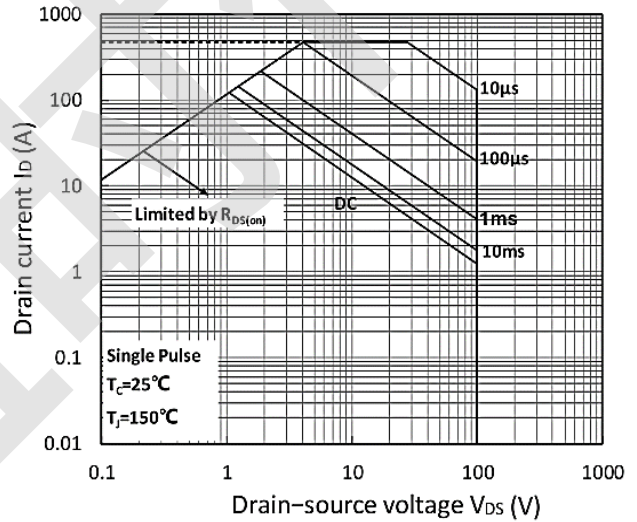
**Figure 7. Capacitance Characteristics**



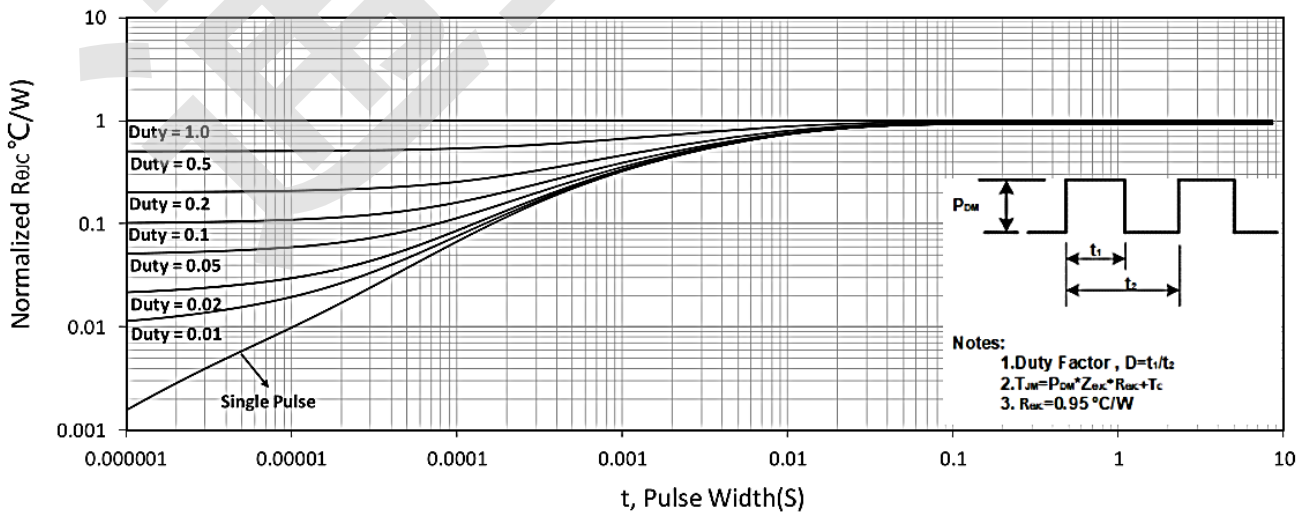
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

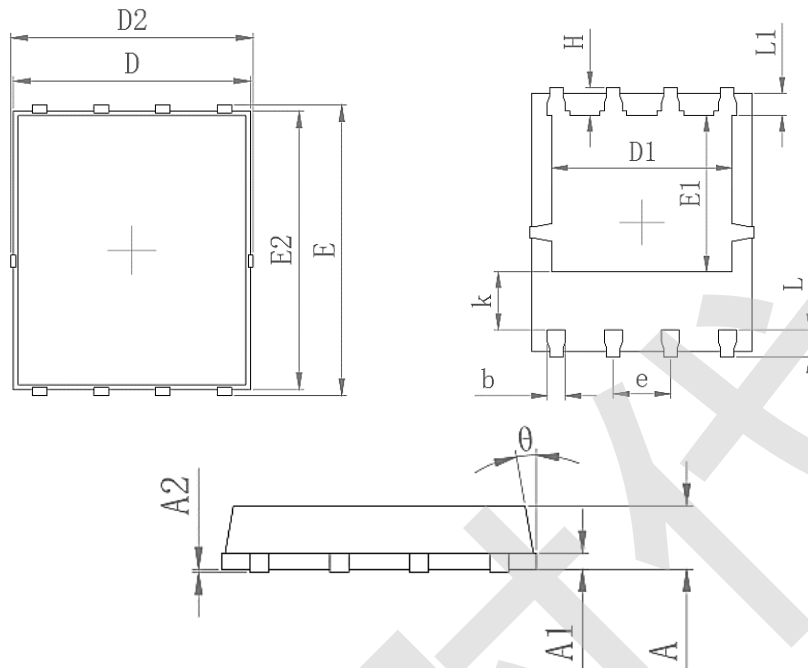


**Figure 10. Safe Operating Area**



**Figure 11. Normalized Maximum Transient Thermal Impedance**

### Package Mechanical Data-PDFN5X6-8L-XZT Single



Symbol	Common	
	mm	
	Mim	Max
A	0.90	1.10
A1	0.254 REF	
A2	0-0.05	
D	4.824	4.976
D1	3.910	4.110
D2	4.944	5.076
E	5.924	6.076
E1	3.375	3.575
E2	5.674	5.826
b	0.350	0.450
e	1.270	
L	0.534	0.686
L1	0.424	0.576
K	1.190	1.390
H	0.549	0.701
Φ	8°	12°

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Edition	Date	Change
Rve1.0	2021/1/31	Initial release

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